

Search Notes

Application/Control No.

10/061,721

Examiner

Jung Park

Applicant(s)/Patent under
Reexamination

KHILL, UZI

Art Unit

2661

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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| Consulted with Chau Nguyen, Christian Laforgia, & Andrew Caldwell 370/401-404, 707/1 (text search only - see histroy printout | 12/27/2005 | JP |
| EAST (USPT, US_PGPUB) - See Search History Printout | 12/27/2005 | JP |
| Internet Search for IEEE Standard | 12/27/2005 | JP |
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